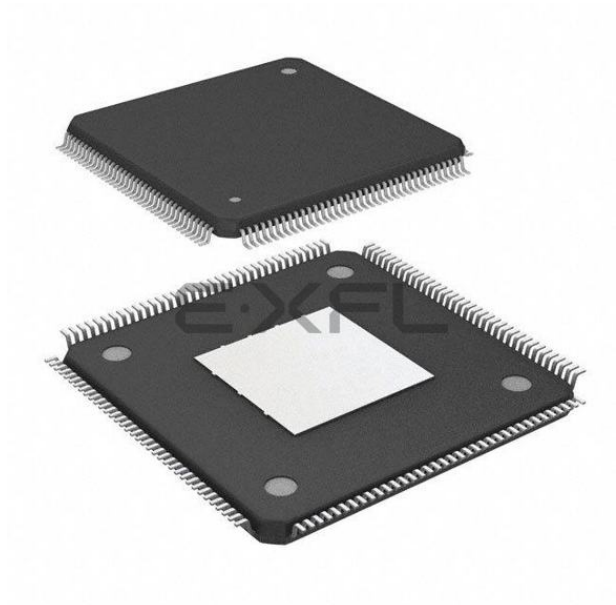

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	3125
Number of Logic Elements/Cells	50000
Total RAM Bits	1677312
Number of I/O	101
Number of Gates	-
Voltage - Supply	2.85V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP Exposed Pad
Supplier Device Package	144-EQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/intel/10m50sce144c8g

Operating Conditions

Intel MAX 10 devices are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of the Intel MAX 10 devices, you must consider the operating requirements described in this section.

Absolute Maximum Ratings

This section defines the maximum operating conditions for Intel MAX 10 devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

Caution: Conditions outside the range listed in the absolute maximum ratings tables may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Single Supply Devices Absolute Maximum Ratings

Table 2. Absolute Maximum Ratings for Intel MAX 10 Single Supply Devices

Symbol	Parameter	Min	Max	Unit
V_{CC_ONE}	Supply voltage for core and periphery through on-die voltage regulator	–0.5	3.9	V
V_{CCIO}	Supply voltage for input and output buffers	–0.5	3.9	V
V_{CCA}	Supply voltage for phase-locked loop (PLL) regulator and analog-to-digital converter (ADC) block (analog)	–0.5	3.9	V

Dual Supply Devices Absolute Maximum Ratings

Table 3. Absolute Maximum Ratings for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Min	Max	Unit
V_{CC}	Supply voltage for core and periphery	–0.5	1.63	V
V_{CCIO}	Supply voltage for input and output buffers	–0.5	3.9	V
V_{CCA}	Supply voltage for PLL regulator (analog)	–0.5	3.41	V

continued...

Symbol	Parameter	Condition	Min	Typ	Max	Unit
		1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
V_{CCA} (1)	Supply voltage for PLL regulator and ADC block (analog)	—	2.85/3.135	3.0/3.3	3.15/3.465	V

Dual Supply Devices Power Supplies Recommended Operating Conditions

Table 7. Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V_{CC}	Supply voltage for core and periphery	—	1.15	1.2	1.25	V
V_{CCIO} (3)	Supply voltage for input and output buffers	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
		1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
V_{CCA}(4)	Supply voltage for PLL regulator (analog)	—	2.375	2.5	2.625	V
V_{CCD_PLL}(5)	Supply voltage for PLL regulator (digital)	—	1.15	1.2	1.25	V
V_{CCA_ADC}	Supply voltage for ADC analog block	—	2.375	2.5	2.625	V
V_{CCINT}	Supply voltage for ADC digital block	—	1.15	1.2	1.25	V

(3) V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities.

(4) All V_{CCA} pins must be powered to 2.5 V (even when PLLs are not used), and must be powered up and powered down at the same time.

(5) V_{CCD_PLL} must always be connected to V_{CC} through a decoupling capacitor and ferrite bead.

Series OCT without Calibration Specifications

Table 13. Series OCT without Calibration Specifications for Intel MAX 10 Devices

This table shows the variation of on-chip termination (OCT) without calibration across process, voltage, and temperature (PVT).

Description	V_{CCIO} (V)	Resistance Tolerance		Unit
		–C7, –I6, –I7, –A6, –A7	–C8	
Series OCT without calibration	3.00	±35	±30	%
	2.50	±35	±30	%
	1.80	±40	±35	%
	1.50	±40	±40	%
	1.35	±40	±50	%
	1.20	±45	±60	%

Series OCT with Calibration at Device Power-Up Specifications

Table 14. Series OCT with Calibration at Device Power-Up Specifications for Intel MAX 10 Devices

OCT calibration is automatically performed at device power-up for OCT enabled I/Os.

Description	V_{CCIO} (V)	Calibration Accuracy	Unit
Series OCT with calibration at device power-up	3.00	±12	%
	2.50	±12	%
	1.80	±12	%
	1.50	±12	%
	1.35	±12	%
	1.20	±12	%

OCT Variation after Calibration at Device Power-Up

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up.

Use the following table and equation to determine the final OCT resistance considering the variations after calibration at device power-up.

Table 15. OCT Variation after Calibration at Device Power-Up for Intel MAX 10 Devices

This table lists the change percentage of the OCT resistance with voltage and temperature.

Description	Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
OCT variation after calibration at device power-up	3.00	0.25	–0.027
	2.50	0.245	–0.04
	1.80	0.242	–0.079
	1.50	0.235	–0.125
	1.35	0.229	–0.16
	1.20	0.197	–0.208

Figure 1. Equation for OCT Resistance after Calibration at Device Power-Up

$$\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV$$

$$\Delta R_T = (T_2 - T_1) \times dR/dT$$

$$\text{For } \Delta R_X < 0; MF_X = 1/(|\Delta R_X|/100 + 1)$$

$$\text{For } \Delta R_X > 0; MF_X = \Delta R_X/100 + 1$$

$$MF = MF_V \times MF_T$$

$$R_{final} = R_{initial} \times MF$$

The definitions for equation are as follows:

- T_1 is the initial temperature.
- T_2 is the final temperature.
- MF is multiplication factor.
- $R_{initial}$ is initial resistance.
- R_{final} is final resistance.

Pin Capacitance

Table 16. Pin Capacitance for Intel MAX 10 Devices

Symbol	Parameter	Maximum	Unit
C_{IOB}	Input capacitance on bottom I/O pins	8	pF
C_{IOLRT}	Input capacitance on left/right/top I/O pins	7	pF
C_{LVDSB}	Input capacitance on bottom I/O pins with dedicated LVDS output (9)	8	pF
C_{ADCL}	Input capacitance on left I/O pins with ADC input (10)	9	pF
$C_{VREFLRT}$	Input capacitance on left/right/top dual purpose V_{REF} pin when used as V_{REF} or user I/O pin (11)	48	pF
C_{VREFB}	Input capacitance on bottom dual purpose V_{REF} pin when used as V_{REF} or user I/O pin	50	pF
C_{CLKB}	Input capacitance on bottom dual purpose clock input pins (12)	7	pF
C_{CLKLRT}	Input capacitance on left/right/top dual purpose clock input pins (12)	6	pF

Internal Weak Pull-Up Resistor

All I/O pins, except configuration, test, and JTAG pins, have an option to enable weak pull-up.

(9) Dedicated LVDS output buffer is only available at bottom I/O banks.

(10) ADC pins are only available at left I/O banks.

(11) When V_{REF} pin is used as regular input or output, F_{max} performance is reduced due to higher pin capacitance. Using the V_{REF} pin capacitance specification from device datasheet, perform SI analysis on your board setup to determine the F_{max} of your system.

(12) 10M40 and 10M50 devices have dual purpose clock input pins at top/bottom I/O banks.

Symbol	Parameter	Condition	Min	Typ	Max	Unit
f_{VCO} (29)	PLL internal voltage-controlled oscillator (VCO) operating range	—	600	—	1300	MHz
f_{INDUTY}	Input clock duty cycle	—	40	—	60	%
$t_{INJITTER\_CCJ}$ (30)	Input clock cycle-to-cycle jitter	F_{INPFD} ≥ 100 MHz	—	—	0.15	UI
		F_{INPFD} < 100 MHz	—	—	±750	ps
f_{OUT_EXT} (28)	PLL output frequency for external clock output	—	—	—	472.5	MHz
f_{OUT}	PLL output frequency to global clock	–6 speed grade	—	—	472.5	MHz
		–7 speed grade	—	—	450	MHz
		–8 speed grade	—	—	402.5	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output	Duty cycle set to 50%	45	50	55	%
t_{LOCK}	Time required to lock from end of device configuration	—	—	—	1	ms
t_{DLOCK}	Time required to lock dynamically	After switchover, reconfiguring any non-post-scale counters or delays, or when `areset` is deasserted	—	—	1	ms
$t_{OUTJITTER\_PERIOD\_IO}$ (31)	Regular I/O period jitter	F_{OUT} ≥ 100 MHz	—	—	650	ps
		F_{OUT} < 100 MHz	—	—	75	mUI
$t_{OUTJITTER\_CCJ\_IO}$ (31)	Regular I/O cycle-to-cycle jitter	F_{OUT} ≥ 100 MHz	—	—	650	ps
		F_{OUT} < 100 MHz	—	—	75	mUI

continued...

(29) The VCO frequency reported by the Intel Quartus Prime software in the PLL summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VCO} specification.

(30) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source, which is less than 200 ps.

(31) Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.99999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied.

Embedded Multiplier Specifications

Table 30. Embedded Multiplier Specifications for Intel MAX 10 Devices

Mode	Number of Multipliers	Power Supply Mode	Performance			Unit
			–I6	–A6, –C7, –I7, –A7	–C8	
9 × 9-bit multiplier	1	Single supply mode	198	183	160	MHz
		Dual supply mode	310	260	210	MHz
18 × 18-bit multiplier	1	Single supply mode	198	183	160	MHz
		Dual supply mode	265	240	190	MHz

Memory Block Performance Specifications

Table 31. Memory Block Performance Specifications for Intel MAX 10 Devices

Memory	Mode	Resources Used		Power Supply Mode	Performance			Unit
		LEs	M9K Memory		–I6	–A6, –C7, –I7, –A7	–C8	
M9K Block	FIFO 256 × 36	47	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz
	Single-port 256 × 36	0	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz
	Simple dual-port 256 × 36 CLK	0	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz
	True dual port 512 × 18 single CLK	0	1	Single supply mode	232	219	204	MHz
				Dual supply mode	330	300	250	MHz

Internal Oscillator Specifications

Table 32. Internal Oscillator Frequencies for Intel MAX 10 Devices

You can access to the internal oscillator frequencies in this table. The duty cycle of internal oscillator is approximately 45%–55%.

Device	Frequency			Unit
	Minimum	Typical	Maximum	
10M02	55	82	116	MHz
10M04				
10M08				
10M16				
10M25				
10M40	35	52	77	MHz
10M50				

UFM Performance Specifications

Table 33. UFM Performance Specifications for Intel MAX 10 Devices

Block	Mode	Interface	Device	Frequency		Unit
				Minimum	Maximum	
UFM	Avalon®-MM slave	Parallel (33)	10M02 (34)	3.43	7.25	MHz
			10M04, 10M08, 10M16, 10M25, 10M40, 10M50	5	116	MHz
		Serial (34)	10M02, 10M04, 10M08, 10M16, 10M25	3.43	7.25	MHz
			10M40, 10M50	2.18	4.81	MHz

(33) Clock source is derived from user, except for 10M02 device.

(34) Clock source is derived from 1/16 of the frequency of the internal oscillator.

Parameter		Symbol	Condition	Min	Typ	Max	Unit
	Integral non linearity	INL	—	–2	—	2	LSB
AC Accuracy	Total harmonic distortion	THD	F_{IN} = 50 kHz, F_S = 1 MHz, PLL	–65 (37)	—	—	dB
	Signal-to-noise ratio	SNR	F_{IN} = 50 kHz, F_S = 1 MHz, PLL	54 (38)	—	—	dB
	Signal-to-noise and distortion	SINAD	F_{IN} = 50 kHz, F_S = 1 MHz, PLL	53 (39)	—	—	dB
On-Chip Temperature Sensor	Temperature sampling rate	T_S	—	—	—	50	kSPS
	Absolute accuracy	—	–40 to 125°C, with 64 samples averaging (40)	—	—	±10	°C
Conversion Rate (41)	Conversion time	—	Single measurement	—	—	1	Cycle
			Continuous measurement	—	—	1	Cycle
			Temperature measurement	—	—	1	Cycle

Related Information

SPICE Models for Intel FPGAs

(37) THD with prescalar enabled is 6dB less than the specification.

(38) SNR with prescalar enabled is 6dB less than the specification.

(39) SINAD with prescalar enabled is 6dB less than the specification.

(40) For the Intel Quartus Prime software version 15.0 and later, Modular ADC Core Intel FPGA IP and Modular Dual ADC Core Intel FPGA IP cores handle the 64 samples averaging. For the Intel Quartus Prime software versions prior to 14.1, you need to implement your own averaging calculation.

(41) For more detailed description, refer to the Timing section in the *Intel MAX 10 Analog-to-Digital Converter User Guide*.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS[53]	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$[54]	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t_{RISE}	Rise time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	Fall time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(53) TCCS specifications apply to I/O banks from the same side only.

(54) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×8	80	—	100	80	—	100	80	—	100	Mbps
		×7	70	—	100	70	—	100	70	—	100	Mbps
		×4	40	—	100	40	—	100	40	—	100	Mbps
		×2	20	—	100	20	—	100	20	—	100	Mbps
		×1	10	—	100	10	—	100	10	—	100	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS(55)	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$(56)	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t_{RISE}	Rise time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	Fall time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(55) TCCS specifications apply to I/O banks from the same side only.

(56) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS[57]	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$[58]	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t_{RISE}	Rise time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	Fall time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(57) TCCS specifications apply to I/O banks from the same side only.

(58) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	170	40	—	170	40	—	170	Mbps
		×2	20	—	170	20	—	170	20	—	170	Mbps
		×1	10	—	170	10	—	170	10	—	170	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS[59]	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$[60]	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t_{RISE}	Rise time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	Fall time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(59) TCCS specifications apply to I/O banks from the same side only.

(60) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×8	80	—	200	80	—	200	80	—	200	Mbps
		×7	70	—	200	70	—	200	70	—	200	Mbps
		×4	40	—	200	40	—	200	40	—	200	Mbps
		×2	20	—	200	20	—	200	20	—	200	Mbps
		×1	10	—	200	10	—	200	10	—	200	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS[67]	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$[68]	Output jitter	—	—	—	1,000	—	—	1,000	—	—	1,000	ps
t_{RISE}	Rise time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	Fall time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(67) TCCS specifications apply to I/O banks from the same side only.

(68) TX jitter is the jitter induced from core noise and I/O switching noise.

LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications

Single Supply Devices LVDS Receiver Timing Specifications

Table 45. LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices

LVDS receivers are supported at all banks.

Symbol	Parameter	Mode	–C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
f_{HSCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	145	5	100	5	100	MHz
		×8	5	145	5	100	5	100	MHz
		×7	5	145	5	100	5	100	MHz
		×4	5	145	5	100	5	100	MHz
		×2	5	145	5	100	5	100	MHz
		×1	5	290	5	200	5	200	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	290	100	200	100	200	Mbps
		×8	80	290	80	200	80	200	Mbps
		×7	70	290	70	200	70	200	Mbps
		×4	40	290	40	200	40	200	Mbps
		×2	20	290	20	200	20	200	Mbps
		×1	10	290	10	200	10	200	Mbps
f_{HSCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	100	5	100	5	100	MHz
		×8	5	100	5	100	5	100	MHz
		×7	5	100	5	100	5	100	MHz
		×4	5	100	5	100	5	100	MHz
		×2	5	100	5	100	5	100	MHz
		×1	5	200	5	200	5	200	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	200	100	200	100	200	Mbps

continued...

Symbol	Parameter	Mode	–C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
		×8	80	200	80	200	80	200	Mbps
		×7	70	200	70	200	70	200	Mbps
		×4	40	200	40	200	40	200	Mbps
		×2	20	200	20	200	20	200	Mbps
		×1	10	200	10	200	10	200	Mbps
SW	Sampling window (high-speed I/O performance pin)	—	—	910	—	910	—	910	ps
	Sampling window (low-speed I/O performance pin)	—	—	1,110	—	1,110	—	1,110	ps
$t_{x\ Jitter}$(71)	Input jitter	—	—	1,000	—	1,000	—	1,000	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	1	—	1	—	1	ms

Dual Supply Devices LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications

Table 46. LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices

LVDS, **TMDS**, **HiSpi**, **SLVS**, and **Sub-LVDS** receivers are supported at all banks.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
f_{HSCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	350	5	320	5	320	MHz
		×8	5	360	5	320	5	320	MHz
		×7	5	350	5	320	5	320	MHz
		×4	5	360	5	320	5	320	MHz

continued...

(71) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
		×2	5	360	5	320	5	320	MHz
		×1	5	360	5	320	5	320	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	700	100	640	100	640	Mbps
		×8	80	720	80	640	80	640	Mbps
		×7	70	700	70	640	70	640	Mbps
		×4	40	720	40	640	40	640	Mbps
		×2	20	720	20	640	20	640	Mbps
		×1	10	360	10	320	10	320	Mbps
f_{HSCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	150	5	150	5	150	MHz
		×8	5	150	5	150	5	150	MHz
		×7	5	150	5	150	5	150	MHz
		×4	5	150	5	150	5	150	MHz
		×2	5	150	5	150	5	150	MHz
		×1	5	300	5	300	5	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	300	100	300	100	300	Mbps
		×8	80	300	80	300	80	300	Mbps
		×7	70	300	70	300	70	300	Mbps
		×4	40	300	40	300	40	300	Mbps
		×2	20	300	20	300	20	300	Mbps
		×1	10	300	10	300	10	300	Mbps
SW	Sampling window (high-speed I/O performance pin)	—	—	510	—	510	—	510	ps

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Date	Version	Changes
December 2017	2017.12.15	• Removed the units for "Input resistance" and "Input capacitance" parameters in the following tables: — *ADC Performance Specifications for Intel MAX 10 Single Supply Devices* — *ADC Performance Specifications for Intel MAX 10 Dual Supply Devices* • Removed the specification with memory initialization for 10M02 device in the *Uncompressed .rbf Sizes for Intel MAX 10 Devices* table.
June 2017	2017.06.16	• Added notes for T_J for Industrial and Automotive devices in Recommended Operating Conditions for Intel MAX 10 Devices table. • Updated the parameter in Internal Weak Pull-Up Resistor for Intel MAX 10 Devices table. • Changed "Performance" to "Frequency" in UFM Performance Specifications for Intel MAX 10 Devices table. • Removed PowerPlay text from tool name.
February 2017	2017.02.21	• Rebranded as Intel.
October 2016	2016.10.31	• Updated the note to the Intel MAX 10 Device Grades and Speed Grades Supported table. • Updated the Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices table.
May 2016	2016.05.02	• Updated t_{RAMP} specifications in Recommended Operating Conditions for Intel MAX 10 Devices table. — Removed standard POR and fast POR specifications. — Updated maximum value from 3 ms to 10 ms and added a not for the minimum value. • Added Supply Current and Power Consumption section. • Added the following tables: — Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices — Internal Configuration Timing Parameter for Intel MAX 10 Devices • Removed POR Delay Specifications for Intel MAX 10 Devices table. • Updated the description in the Internal Configuration Time section. • Updated the following tables: — Internal Configuration Time for Intel MAX 10 Devices (Uncompressed `.rbf`) — Internal Configuration Time for Intel MAX 10 Devices (Compressed `.rbf`)

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Date	Version	Changes
May 2015	2015.05.04	• Updated a note to V_{CCIO} for both single supply and dual supply power supplies recommended operating conditions tables. Note updated: V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities. • Updated Example for OCT Resistance Calculation after Calibration at Device Power-Up. • Removed a note to BLVDS in Differential I/O Standards Specifications for Intel MAX 10 Devices table. BLVDS is now supported in Intel MAX 10 single supply devices. Note removed: BLVDS TX is not supported in single supply devices. • Updated ADC Performance Specifications for both single supply and dual supply devices. — Changed the symbol for Operating junction temperature range parameter from T_A to T_J. — Edited sampling rate maximum value from 1000 kSPS to 1 MSPS. — Added a note to analog input voltage parameter. — Removed input frequency, f_{IN} specification. — Updated the condition for DNL specification: External V_{REF}, no missing code. Added DNL specification for condition: Internal V_{REF}, no missing code. — Added notes to AC accuracy specifications that the value with prescalar enabled is 6dB less than the specification. — Added a note to On-Chip Temperature Sensor (absolute accuracy) parameter about the averaging calculation. • Updated ADC Performance Specifications for Intel MAX 10 Single Supply Devices table. — Added condition for On-Chip Temperature Sensor (absolute accuracy) parameter: with 64 samples averaging. • Updated ADC Performance Specifications for Intel MAX 10 Dual Supply Devices table. — Updated Digital Supply Voltage minimum value from 1.14 V to 1.15 V and maximum value from 1.26 V to 1.25 V. • Updated f_{HSCLK} and HSIODR specifications for –A7 speed grade in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices — LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices

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Date	Version	Changes
		• Updated SSTL-2 Class I and II I/O standard specifications for JEDEC compliance as follows: — VIL(AC) Max: Updated from V_{REF} – 0.35 to V_{REF} – 0.31 — VIH(AC) Min: Updated from V_{REF} + 0.35 to V_{REF} + 0.31 • Added a note to BLVDS in Differential I/O Standards Specifications for Intel MAX 10 Devices table: BLVDS TX is not supported in single supply devices. • Added a link to MAX 10 High-Speed LVDS I/O User Guide for the list of I/O standards supported in single supply and dual supply devices. • Added a statement in PLL Specifications for Intel MAX 10 Single Supply Device table: For V36 package, the PLL specification is based on single supply devices. • Added Internal Oscillator Specifications from Intel MAX 10 Clocking and PLL User Guide. • Added UFM specifications for serial interface. • Updated total harmonic distortion (THD) specifications as follows: — Single supply devices: Updated from 65 dB to –65 dB — Dual supply devices: Updated from 70 dB to –70 dB (updated from 65 dB to –65 dB for dual function pin) • Added condition for On-Chip Temperature Sensor—Absolute accuracy parameter in ADC Performance Specifications for Intel MAX 10 Dual Supply Devices table. The condition is: with 64 samples averaging. • Updated the description in Periphery Performance Specifications to mention that proper timing closure is required in design. • Updated HSIODR and f_{HSCLK} specifications for x10 and x7 modes in True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices. • Added specifications for low-speed I/O performance pin sampling window in LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices table: Max = 900 ps for –C7, –I7, –A7, and –C8 speed grades. • Added $t_{RU\_nCONFIG}$ and $t_{RU\_nRSTIMER}$ specifications for different devices in Remote System Upgrade Circuitry Timing Specifications for Intel MAX 10 Devices table. • Removed the word "internal oscillator" in User Watchdog Timer Specifications for Intel MAX 10 Devices table to avoid confusion. • Added IOE programmable delay specifications.
September 2014	2014.09.22	Initial release.